

Application/Control No.	Applicant(s)/Patent unde Reexamination	г
10/717,597	TWINE ET AL.	
Examiner	Art Unit	
Sue Liu	1639	

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
PGPB, USPT, USOC, EPAB, JPAB, DWPI. (See attached search strategy)	5/16/2006	SL		
Inventor Name Search on PALM	5/16/2006	SL		